



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Paul B. Mirkarimi et al.                      Docket No. : CIL-10972  
Serial No. : 10/086,614                                      Art Unit : 1762  
Filed : March 1, 2002                                      Examiner : W. Markham  
For : Ion-Assisted Deposition Techniques For  
The Planarization Of Topological Defects

AMENDMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the Office Action mailed April 21, 2006, please amend the  
above-referenced application as follows: